L Number	Hits	Search Text	DB	Time stamp
-	56177	(test\$3) near (DUT CUT SUT circuit\$2 "device under test" "circuit under test" "system under test")	USPAT; US-PGPUB; EPO; JPO; DERWENT;	2004/02/16 16:54
-	23982	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits)))	IBM_TDB USPAT; US-PGPUB; EPO, JPO; DERWENT;	2004/02/16 16:56
-	9894	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))) ab. ((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))).ti. ((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))).clm.	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 16:58
-	918	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))) and 714/724.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/02/16 16:57
-	93	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))) and 714/725.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 16:59
-	149	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))) and 714/731.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 16:58
-	464	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))) and 714/733.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 16:58
-	240	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))) and 714/734.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/02/16 16:59
-	354	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))) and 714/736.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/02/16 16:59
-	454	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))) and 714/738.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 16:59
-	66	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))) and 714/741.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 17:00
-	123	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))) and 714/744.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 17:00

-	6272	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal	USPAT;	2004/02/16 17:00
		signals information input bit bits))).ab.	US-PGPUB, EPO, JPO, DERWENT;	·
-	1093	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal	IBM_TDB USPAT; US-PGPUB;	2004/02/16 17:00
		signals information input bit bits))) and ("operating system")	EPO; JPO; DERWENT; IBM_TDB	·
-	20	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits) and (software simulation configuration))) and 714/744.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT;	2004/02/16 17:01
-	12	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits) and (software simulation))) and 714/744.ccls.	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2004/02/16 17:01
-	1040	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits) and (software simulation)))	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2004/02/16 17:02
-	2120	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits) and (software simulation configuration)))	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2004/02/16 17:02
-	445	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits) and (software simulation) and (device driver)))	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2004/02/16 17:02
-	53	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits) and (software simulation) and (driver)))	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2004/02/16 17:04
-	1588	(test\$3 near (("semiconductor device" DUT CUT SUT circuit circuits "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits)) and (software simulation) and driver)	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2004/02/16 17:06
-	14	(test\$3 near (("semiconductor device" DUT CUT SUT circuit circuits "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits)) and (software simulation) and driver).clm.	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2004/02/16 17:07
-	8	(test\$3 near (("semiconductor device" DUT CUT SUT circuit circuits "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits)) and (software simulation) and driver).ab.	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2004/02/16 17:09
-	2	6578166.pn.	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 17:14

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-	. 2	6678643.pn.	USPAT;	2004/02/16 17:14
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-	2	6591205.pn.	USPAT;	2004/02/16 17:12
			US-PGPUB;	
			ЕРО; ЛРО;	
			DERWENT;	
			IBM_TDB	
-	2	5557559.pn.	USPAT;	2004/02/16 17:12
			US-PGPUB;	
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			IBM_TDB	
-	2	5497378.pn.	USPAT;	2004/02/16 17:12
			US-PGPUB;	
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	0	(6678643.pn. and 6678643.pn. and 6591205.pn. and 5557559.pn. and	USPĀT;	2004/02/16 17:19
		5497378.pn.) and (test\$3 simulation evaluat\$3 DUT CUT SUT circuit\$2	US-PGPUB;	
		"device under test" "circuit under test" "system under test" data pattern	ЕРО; ЛРО;	
	,	patterns signal signals information input bit bits)	DERWENT;	
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_	2	(6678643.pn.) and (test\$3 simulation evaluat\$3 DUT CUT SUT	USPAT;	2004/02/16 17:18
	_	circuit\$2 "device under test" "circuit under test" "system under test" data	US-PGPUB;	200 110 27110
1		pattern patterns signal signals information input bit bits)	ЕРО; ЛРО;	
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	2	(5557559.pn.) and (test\$3 simulation evaluat\$3 DUT CUT SUT	USPAT;	2004/02/16 17:18
		circuit\$2 "device under test" "circuit under test" "system under test" data	US-PGPUB;	2004/02/10 17.16
		pattern patterns signal signals information input bit bits)	ЕРО; ЛРО;	·
		pattern patterns signal signals information input of ofts)	DERWENT;	
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_	_	"device under test" "circuit under test" "system under test" data pattern	US-PGPUB;	2004/02/10 17.16
		patterns signal signals information input bit bits)	EPO; JPO;	
		patterns signal signals information input of ofts)	DERWENT;	
	່	(6591205.pn.) and (test\$3 simulation evaluat\$3 DUT CUT SUT	IBM_TDB	2004/02/15 17:19
-	2	circuit\$2 "device under test" "circuit under test" "system under test" data	USPAT;	2004/02/16 17:18
		pattern patterns signal signals information input bit bits)	US-PGPUB; EPO; JPO;	
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		patterns signal signals information input bit bits)	DERWENT;	
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-	8	(6678643.pn. or 6678643.pn. or 6591205.pn. or 5557559.pn. or	USPAT;	2004/02/16 17:24
		5497378.pn.) and (test\$3 simulation evaluat\$3 DUT CUT SUT circuit\$2	US-PGPUB;	
		"device under test" "circuit under test" "system under test" data pattern	ЕРО; ЛРО;	
		patterns signal signals information input bit bits driver)	DERWENT;	
			IBM_TDB	